## Notice of References Cited Application/Control No. | Applicant(s)/Patent Under Reexamination | NAGEL ET AL. | Examiner | Art Unit | Leith A Al-Nazer | 2821 | Page 1 of 1

## **U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
	Α	US-6,061,025	05-2000	Jackson et al.	343/700MS
	В	US-6,806,831 B2	10-2004	Johansson et al.	343/700MS
	С	US-6,650,302 B2	11-2003	Sanad, Mohamed Said	343/841
	D	US-6,404,394 B1	06-2002	Hill, Robert	343/702
	E	US-5,767,808	06-1998	Robbins et al.	343/700MS
	F	US-6,417,816 B2	07-2002	Sadler et al.	343/795
	G	US-2003/0071757 A1	04-2003	Yamaki, Kazuhisa	343/741
	Н	US-2003/0210188 A1	11-2003	Hebron et al.	343/700.0MS
	ı	US-5,134,422	07-1992	Auriol, Albert	343/895
	J	US-			
	К	US-			
	L	US-			
	М	US-			

## **FOREIGN PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	Ν					
	0					
	Р					
	ø					
	R					
	S					
	Т					

## **NON-PATENT DOCUMENTS**

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
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	w	
	x	

\*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).) Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.